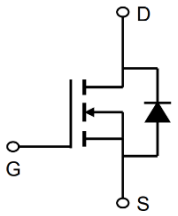
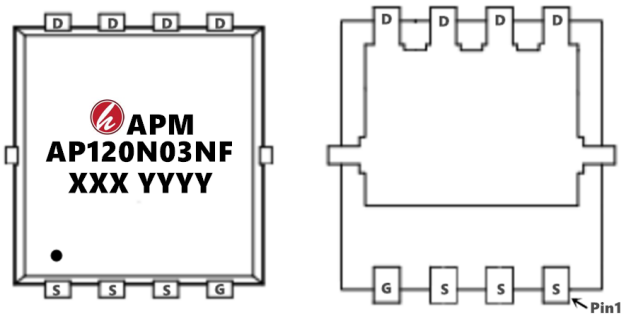
AP120N03NF

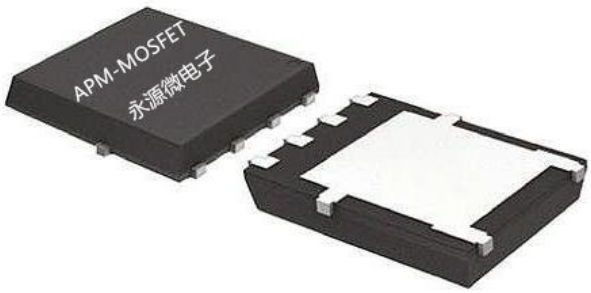
30V N-Channel Enhancement Mode MOSFET

Description

The AP120N03NF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.







General Features

V_{DS} = 30V I_D =120A

$R_{DS(ON)}$ < 2.4mΩ @ V_{GS}=10V

Application

Lithium battery protection

Wireless impact

Mobile phone fast charging

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP120N03NF	PDFN5*6-8L	AP120N03NF XXX YYYY	5000

Absolute Maximum Ratings (T_C=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	30	V
VGS	Gate-Source Voltage	±20	V
I_D@T_C=25℃	Continuous Drain Current, V_{GS} @ 10V[1,6]	120	A
I_D@T_C=100℃	Continuous Drain Current, V_{GS} @ 10V[1,6]	66	A
IDM	Pulsed Drain Current[2]	320	A
EAS	Single Pulse Avalanche Energy[3]	180	mJ
IAS	Avalanche Current	60	A
P_D@T_C=25℃	Total Power Dissipation[4]	187	W
TSTG	Storage Temperature Range	-55 to 150	℃
T_J	Operating Junction Temperature Range	-55 to 150	℃
$R_{\theta}JA$	Thermal Resistance Junction-Ambient [1]	62	℃/W
$R_{\theta}JC$	Thermal Resistance Junction-Case[1]	1.1	℃/W

Electrical Characteristics (T_J=25℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V_{GS}=0V , I_D=250uA	30	32	---	V
△BVDSS/△TJ	BV_{DSS} Temperature Coefficient	Reference to 25℃ , I_D=1mA	---	0.014	---	V/℃
RDS(ON)	Static Drain-Source On-Resistance[2]	V_{GS}=10V , I_D=30A	---	2.0	2.4	mΩ
		V_{GS}=4.5V , I_D=15A	---	3.5	4.5	
VGS(th)	Gate Threshold Voltage	V_{GS}=V_{DS} , I_D =250uA	1.2	1.5	2.5	V
△$V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	-4	---	mV/℃
IDSS	Drain-Source Leakage Current	V_{DS}=24V , V_{GS}=0V , T_J=25℃	---	---	1	uA
		V_{DS}=24V , V_{GS}=0V , T_J=55℃	---	---	5	
IGSS	Gate-Source Leakage Current	V_{GS}=±20V , V_{DS}=0V	---	---	±100	nA
gfs	Forward Transconductance	V_{DS}=5V , I_D=30A	---	50	---	S
R_g	Gate Resistance	V_{DS}=0V , V_{GS}=0V , f=1MHz	---	1.7	---	Ω
Q_g	Total Gate Charge (4.5V)	V_{DS}=15V , V_{GS}=10V , I_D=15A	---	56.9	---	nC
Qgs	Gate-Source Charge		---	13.8	---	
Qgd	Gate-Drain Charge		---	23.5	---	
Td(on)	Turn-On Delay Time	V_{DD}=15V , V_{GS}=10V , R_G=3.3Ω, I_D=1A	---	20.1	---	ns
T_r	Rise Time		---	6.3	---	
Td(off)	Turn-Off Delay Time		---	124.6	---	
T_f	Fall Time		---	15.8	---	
Ciss	Input Capacitance	V_{DS}=15V , V_{GS}=0V , f=1MHz	---	4345	---	pF
Coss	Output Capacitance		---	340	---	
Crss	Reverse Transfer Capacitance		---	225	---	
IS	Continuous Source Current[1,6]	V_G=V_D=0V , Force Current	---	---	85	A
VSD	Diode Forward Voltage[2]	V_{GS}=0V , I_S=1A , T_J=25℃	---	---	1.2	V

Note :

1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2、The data tested by pulsed , pulse width ≦ 300us , duty cycle ≦ 2%

3、The EAS data shows Max. rating . The test condition is V DD =25V,V GS =10V,L=0.1mH,I AS =60A

4、The power dissipation is limited by 150℃ junction temperature

5、The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

Typical Characteristics

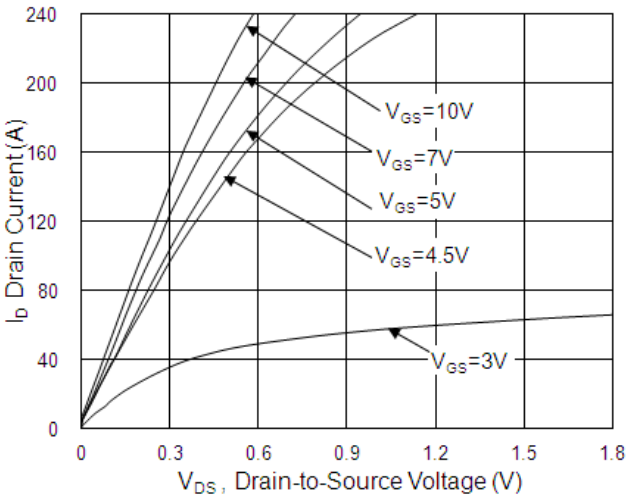


Fig.1 Typical Output Characteristics

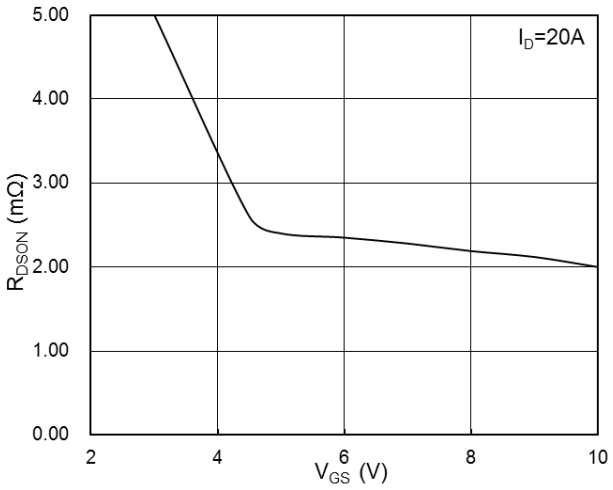


Fig.2 On-Resistance v.s Gate-Source

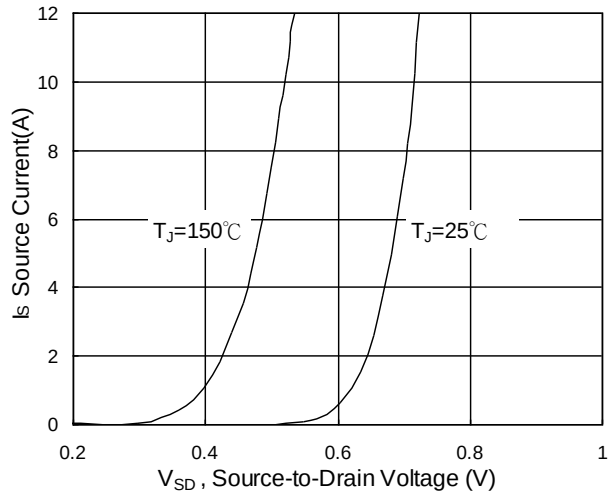


Fig.3 Forward Characteristics of Reverse

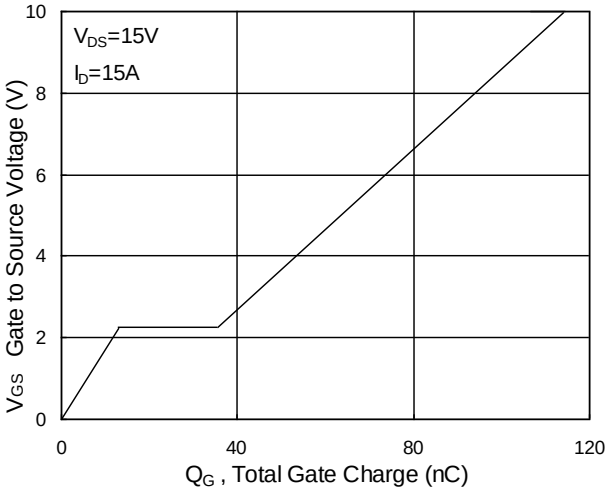


Fig.4 Gate-Charge Characteristics

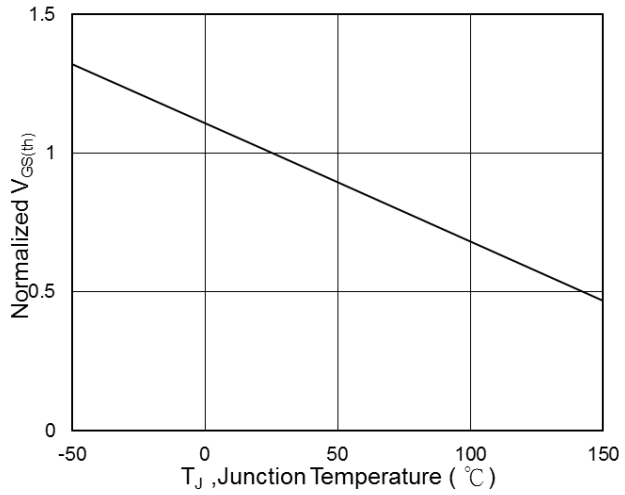


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

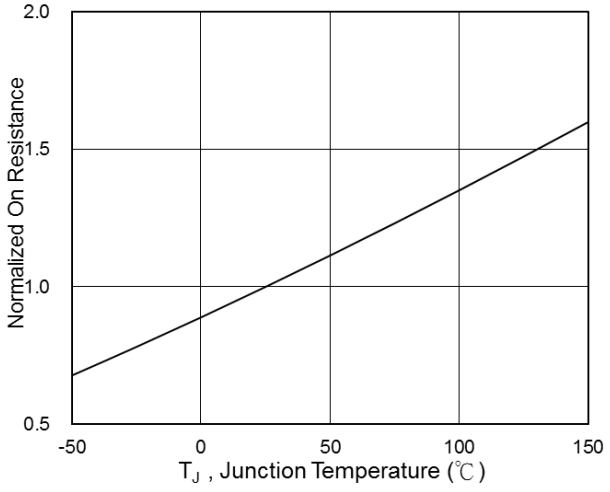


Fig.6 Normalized R_{DSON} v.s T_J

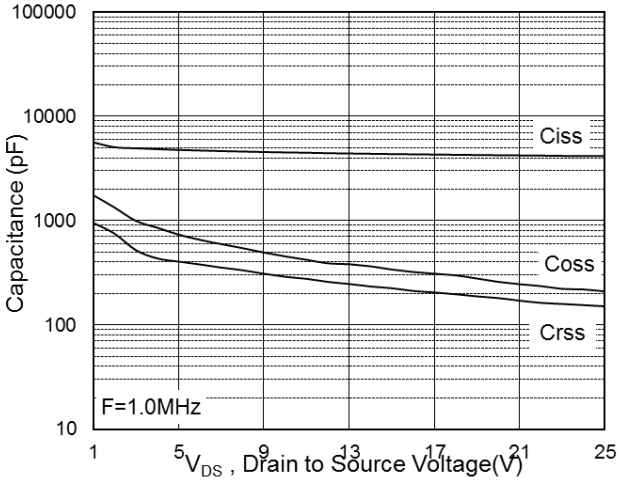


Fig.7 Capacitance

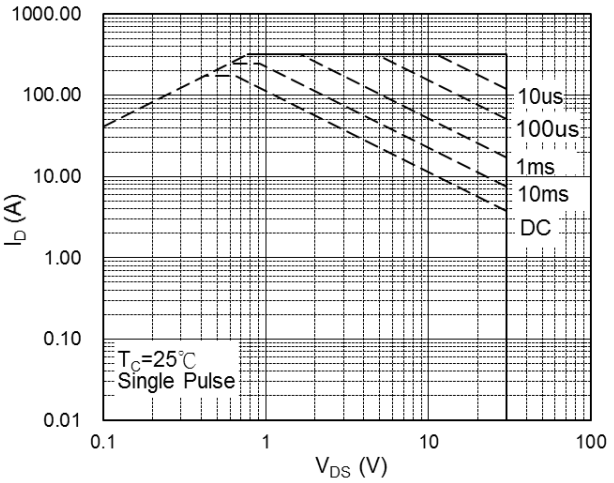


Fig.8 Safe Operating Area

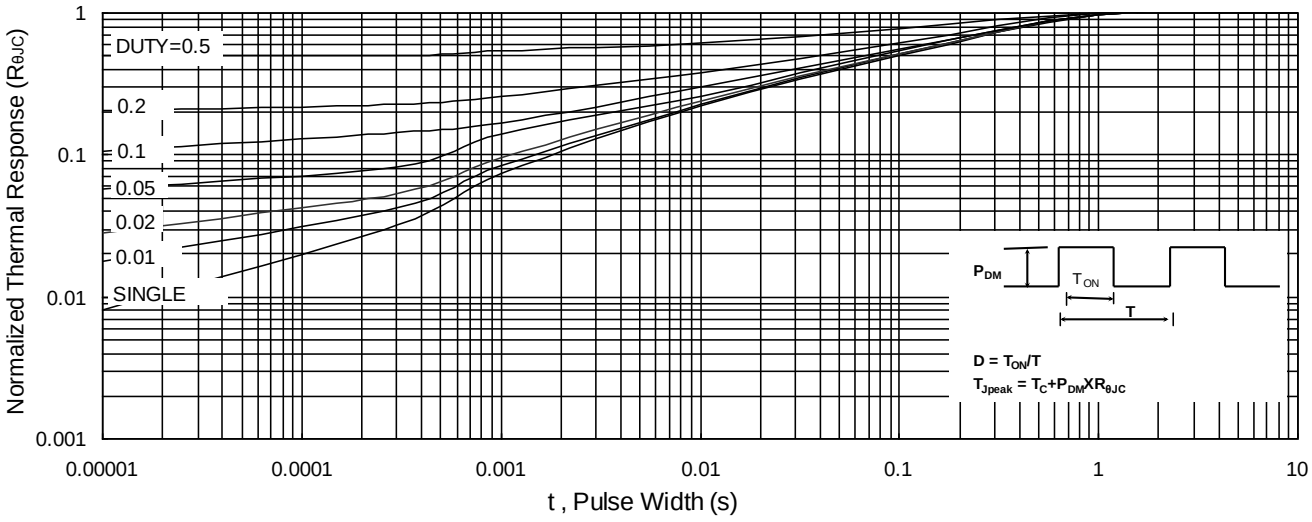


Fig.9 Normalized Maximum Transient Thermal Impedance

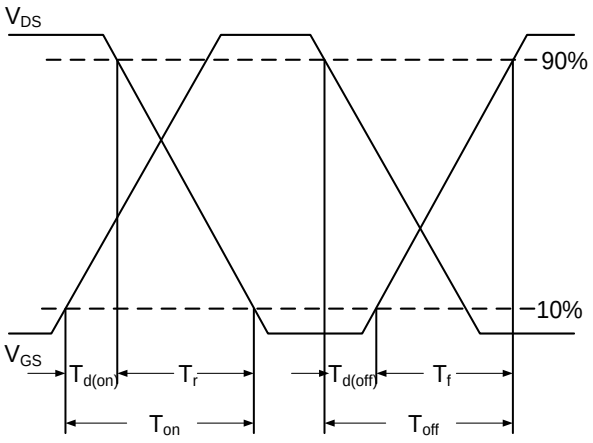


Fig.10 Switching Time Waveform

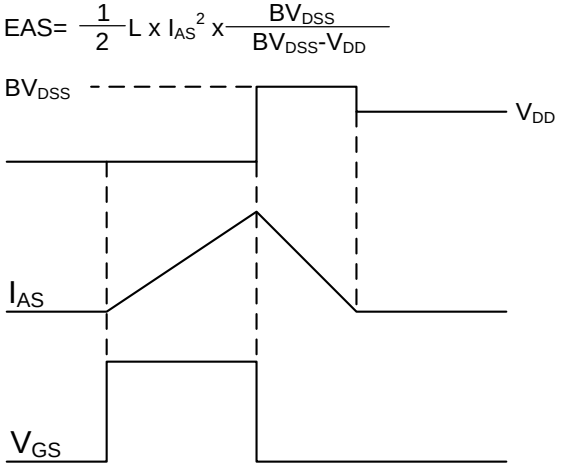


Fig.11 Unclamped Inductive Switching Waveform

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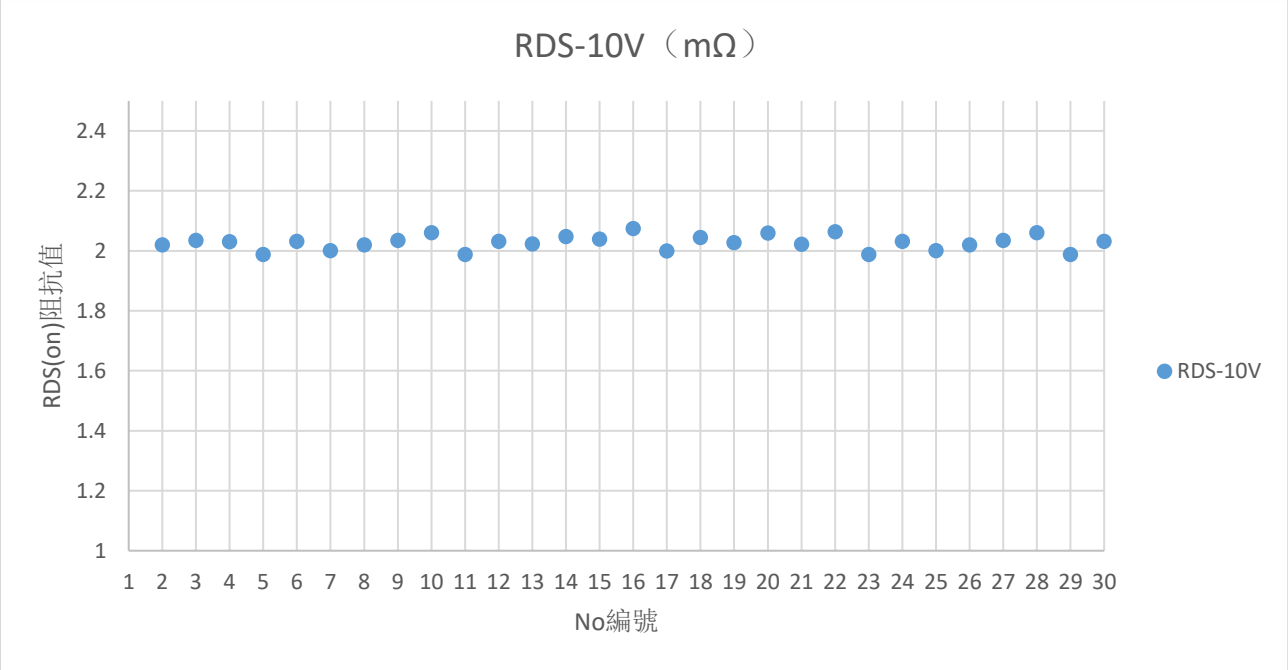
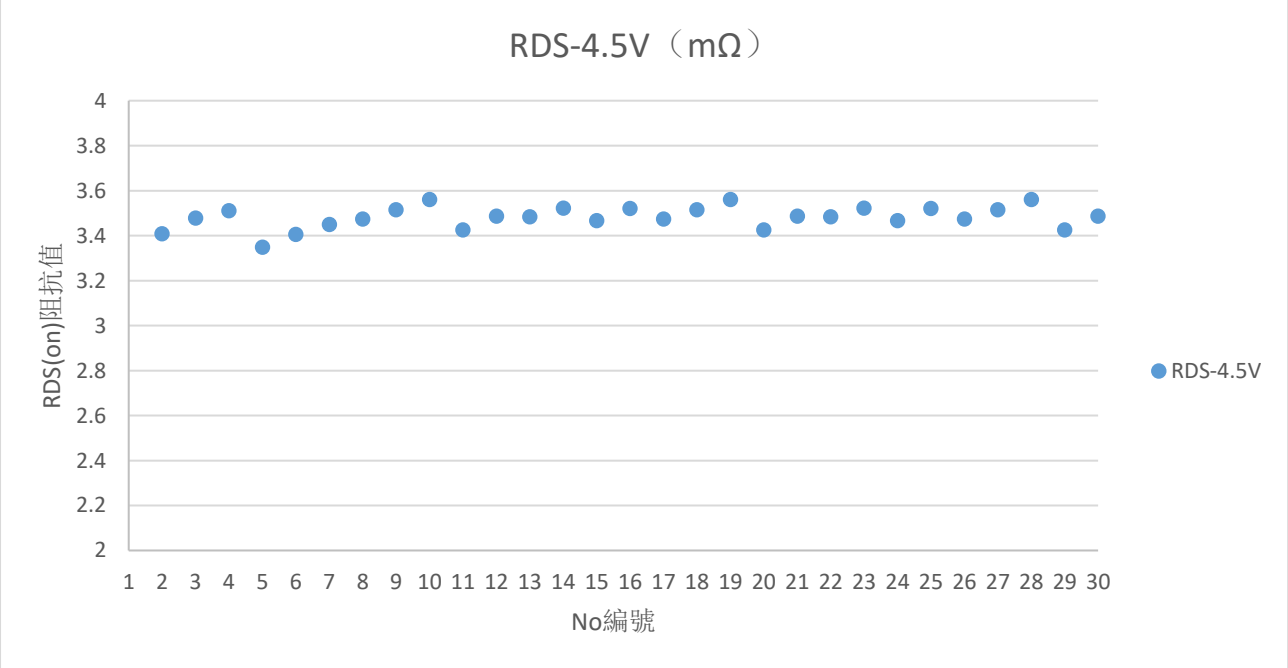
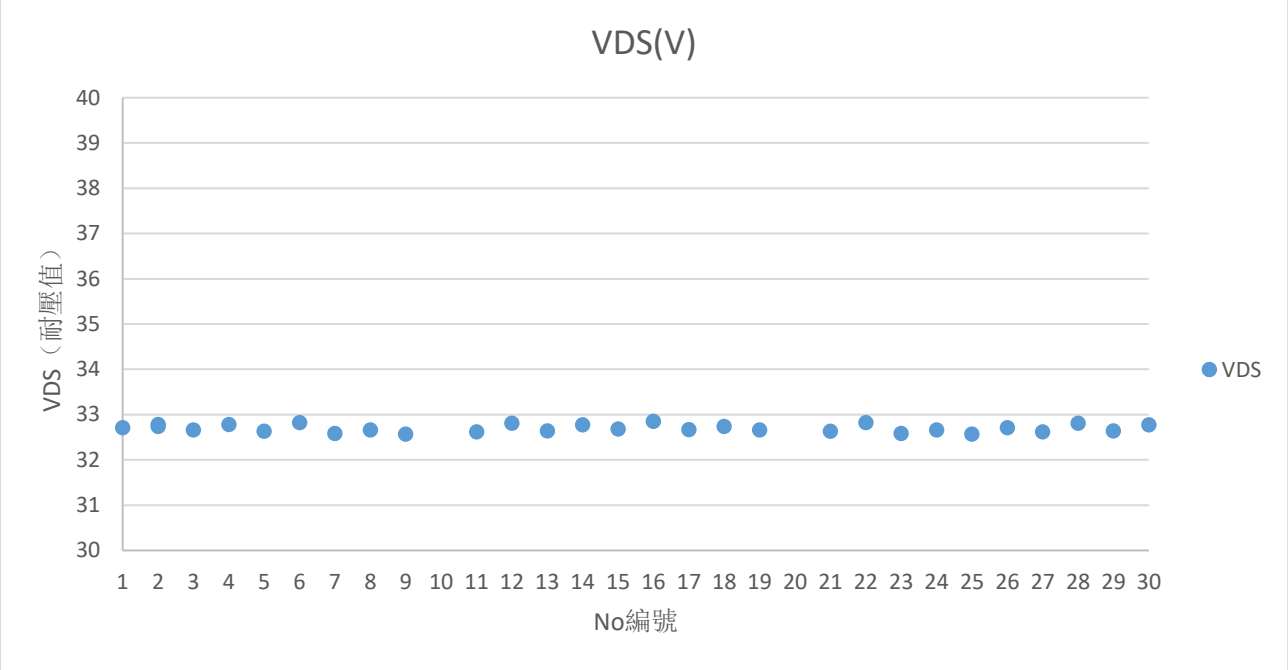
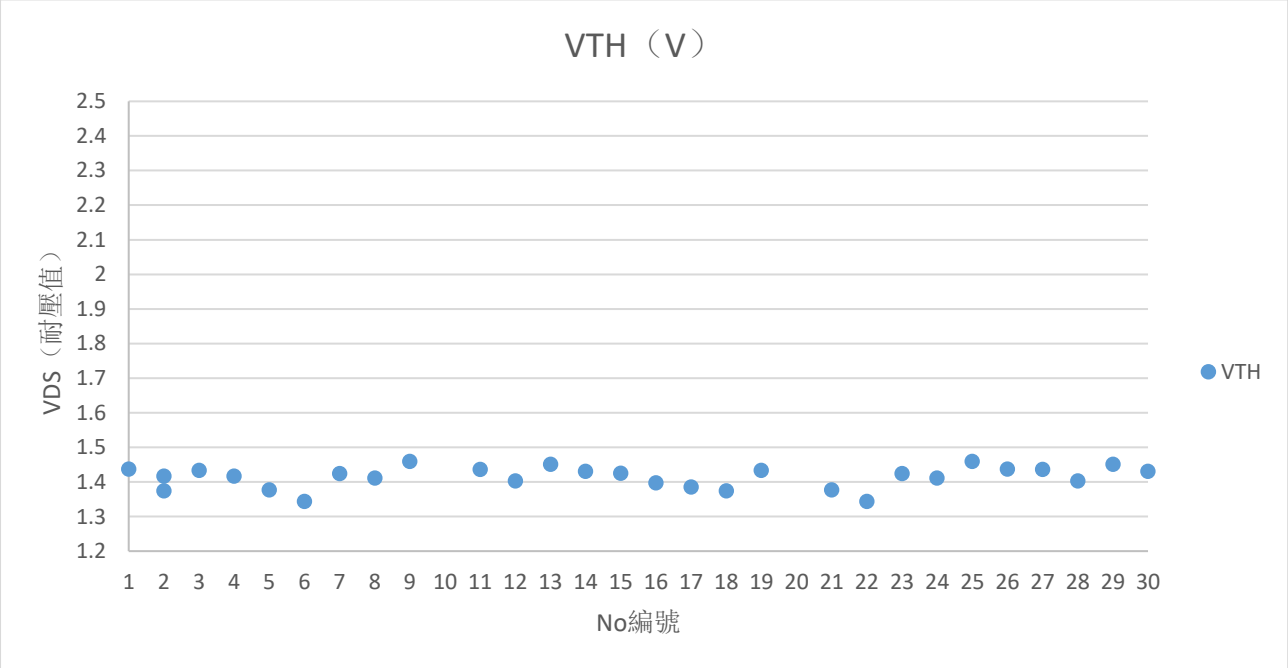
Edition	Date	Change
Rve1.0	2019/4/10	Initial release
Rve2.0	2020/7/8	

Test Report For 30PCS（30pcs 典型測試報告）






VDS(V)
VDS（耐壓值）
40
39
38
37
36
35
34
33
32
31
30
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28 29 30
No編號
VDS


VTH（V）
VDS（耐壓值）
2.5
2.4
2.3
2.2
2.1
2
1.9
1.8
1.7
1.6
1.5
1.4
1.3
1.2
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28 29 30
No編號
VTH